

Notice of References Cited	Application/Control No. 09/757,491	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Jennifer T Nguyen	Art Unit 2674	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,708,454	01-1998	Kato et al.	345/100
	B	US-6,225,969	05-2001	Ishii	345/100
	C	US-6,522,315	02-2003	Ozawa et al.	345/92
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Taguchi et al. Pub. No. US 2002/0153881
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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